

SYSTEM		
ZYGO P/N	6306-0360-04	system with full enclosure
	6306-0360-05	system with 1/2 height enclosure
Measurement Technique	3D coherence scanning interferometry, SureScan™ technology	
Scanner	Precision Piezo drive with Closed loop capacitance gauge control and crash protection	
Objectives	1.0X – 100X magnification; Standard and long working distance; See the Nexview & NewView 9000 Series Objective Chart for more details	
Objective Mounting Options	<ul style="list-style-type: none">• Single objective dovetail• Manual Encoded 4-position turret• Motorized 4-position turret	
Optical Zoom	Motorized 3-position encoded zoom <ul style="list-style-type: none">• 0.5X, 1.0X, 2.0X included• 0.75X, 1.5X optional	
Field of View	Objective and zoom selectable from 0.04 x 0.04 mm to 17.49 x 17.49 mm; Integrated field stitching for larger areas	
Illuminator	Proprietary solid-state white light source with software-selectable field stop, aperture stop and spectral filters	
Measurement Array	Selectable 1600 x 1200, 1000 x 1000, 1000 x 600, 1000 x 200	
Part Viewing	Selectable Monochrome imaging with available fringe-free viewing mode	
Focus	Motorized manual or auto focus with Part Finder and Smart Setup Technology	
Z-Drive (Focus) Stage	150 mm range with 0.1 µm resolution	
Part Stage	Encoded linear motor drive with 650 x 650 mm XY travel range	
Stage Configuration	Split axis gantry style; X-stage translates Head; Y-stage translates the sample	
Sample Holder	Custom vacuum sample holders up to 650 x 650 mm available	
System Controller	i7 class PC with 1080P display	
Software	ZYGO Mx software running under Microsoft Windows 10 (64-bit)	
PHYSICAL		
Dimensions (HWD)	System with enclosure: 166 x 140 x 164 cm	
Weight	System: 1830 kg System with enclosure: 1955 kg	
UTILITY REQUIREMENTS		
Input Voltage	100 to 240 VAC, 50/60 Hz	
Compressed Air for isolation	4.1 to 5.5 bar (60 to 80 psi); dry and filtered; 1/4 in. input	
Vacuum	Optional from a customer supplied source, based on part stage requirements	

PERFORMANCE	
Vertical Scan Range	150 µm with precision Piezo drive; 20 mm with extended scan
Surface Topography Repeatability ⁽¹⁾	0.12 nm
Repeatability of RMS ⁽²⁾	0.01 nm
Optical Lateral Resolution ⁽³⁾	0.34 µm (100X objective)
Spatial Sampling	0.04 µm (100X objective 2X zoom)
Maximum Data Scan Speed ⁽⁴⁾	53 µm/sec @ 1600 x 1200 69 µm/sec @ 1000 x 1000 107 µm/sec @ 1000 x 600 171 µm/sec @ 1000 x 200
Step Height Repeatability ⁽⁵⁾	0.1%
Step Height Accuracy ⁽⁶⁾	0.3%
TEST PART CHARACTERISTICS	
Material	Opaque, transparent, coated, uncoated, specular, rough
Maximum Sample Height	260 mm under X axis Crossbeam 329 mm under typ. objective focus
Maximum Surface Slope	55° – smooth part @ 100X 85° – scattering surface
Sample Reflectivity	0.05% - 100%
ENVIRONMENTAL REQUIREMENTS	
Temperature	15 to 30°C with rate of change <1.0°C per 15 min
Humidity	5 to 95% relative, noncondensing
Vibration Isolation	Included and required for vibration in the range of 1 Hz to 120 Hz
Vibration Criterion	VC-C or better
Acoustic Criterion	NC30 or better

FOOTNOTES

Performance specifications under laboratory conditions using standard specimens, according to ISO 25178-601, 25178-604 and 5436-1.

- (1) Surface Topography Repeatability for CSI mode, 1-sec acquisition, full FOV with 3x3 median filter, in a laboratory environment.
- (2) Repeatability of the RMS surface roughness parameter Sq, under the same conditions as for (1). Note that the repeatability of the Sq is sometimes referred to informally as "vertical resolution."
- (3) Lateral Resolution=Sparrow criterion, objective dependent.
- (4) Data scan speed depends on the measurement array and data acquisition mode.
- (5) 1-σ Step height repeatability verified using 1.8 µm and 24 µm ZYGO certified step height standards.
- (6) Instrument contribution to uncertainty for step height measurements using the piezo drive.

Specifications subject to change without prior notice.